

<div style="display: flex; justify-content: space-between;"><div>10596614 - GAU: 1795</div><div>ATTY DOCKET NO. FIS920020101US1</div><div>APPLICATION NO. 10/596,614</div></div> <div style="text-align: center; margin-top: 10px;">INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i></div>				APPLICANT(S) Christopher Ausschnitt				
				FILING DATE 06/19/2006		GROUP ART UNIT N/A		
				U.S. PATENT DOCUMENTS				
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
		6,423,977	07/23/2002	Hayasaki, et al.				
		6,323,946	11/27/2001	Norton				
		5,968,691	10/19/1999	Yoshioka, et al.				
		5,363,171	11/08/1994	Mack				
		5,917,594	06/29/1999	Norton				
U.S. PATENT APPLICATION PUBLICATIONS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER /Christopher Young/ (06/18/2009)				DATE CONSIDERED 06/18/2009				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
Christopher Ausschnitt		
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,451,621	09/17/2002	Rangarajan, et al.			
	6,433,871	08/13/2002	Lensing, et al.			
	5,631,721	05/20/1997	Stanton, et al.			
	5,965,309	10/12/1999	Ausschnitt, et al.			
	5,629,772	05/13/1997	Ausschnitt			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER /Christopher Young/ (06/18/2009)

DATE CONSIDERED 06/18/2009

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
Christopher Ausschnitt		
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,976,740	11/02/1999	Ausschnitt, et al.			
	5,880,838	03/09/1999	Marx, et al.			
	6,429,930	08/06/2002	Littau, et al.			
	6,432,729	08/13/2002	Mundt, et al.			
	6,051,349	04/18/2000	Yoshioka, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
--	-------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
Christopher Ausschnitt		
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,259,521	07/10/2001	Miller, et al.			
	6,388,253	05/14/2002	Su			
	6,429,943	08/06/2002	Opsal, et al.			
	5,739,909	04/14/1998	Blayo, et al.			
	6,383,824	05/07/2002	Lensing			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
--	-----------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
	Christopher Ausschnitt	
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,703,692	12/30/1997	McNeil, et al.			
	6,433,878	08/13/2002	Niu, et al.			
	6,485,891	11/26/2002	Noguchi, et al.			
	6,223,139	04/24/2001	Wong, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2002/0027648	03/07/2002	Van Der Laan, et al.			
	20030169423	09/11/2003	Finarov, et al.			
	20030155537	08/21/2003	Machavariani, et al.			
	20030086097	05/08/2003	Finarov			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER /Christopher Young/ (06/18/2009)

DATE CONSIDERED 06/18/2009

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. FIS920020101US1		APPLICATION NO. 10/596.614		
				APPLICANT(S) Christopher Ausschnitt				
				FILING DATE 06/19/2006		GROUP ART UNIT N/A		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
		6,171,731	01/09/2001	Medvedeva, et al.				
		5,916,711	06/29/1999	Salik, et al.				
		6,052,626	04/18/2000	Inui				
		6,263,299	07/17/2001	Aleshin, et al.				
		5,644,390	07/01/1997	Yasuzato				
U.S. PATENT APPLICATION PUBLICATIONS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
EXAMINER /Christopher Young/ (06/18/2009)				DATE CONSIDERED 06/18/2009				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	ATTY DOCKET NO. FIS920020101US13	APPLICATION NO. 10/596,614
	Christopher Ausschnitt	
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,867,276	02/02/1999	McNeil, et al.			
	5,559,601	09/24/1996	Gallatin, et al.			
	6,259,513	07/10/2001	Gallatin, et al.			
	5,712,707	01/27/1998	Ausschnitt, et al.			
	5,757,507	05/26/1998	Ausschnitt, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
---	--------------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
	Christopher Ausschnitt	
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,869,739	03/22/2005	Ausschnitt, et al.			
		6,183,919	02/06/2001	Ausschnitt, et al.			
		6,130,750	10/10/2000	Ausschnitt, et al.			
		6,879,400	04/12/2005	Ausschnitt, et al.			
		5,682,242	10/28,1997	Eylon			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
---	--------------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
	Christopher Ausschnitt	
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,517,312	05/14/1996	Finarov			
	6,704,920	03/09/2004	Brill, et al.			
	6,657,736	12/02/2003	Finarov, et al.			
	6,650,424	11/18/2003	Brill, et al.			
	6,643,017	11/04/2003	Cohen, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
---	--------------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<p>10596614 - GAU: 1795</p> <p>INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)</p>	<p>ATTY DOCKET NO. FIS920020101US1</p>	<p>APPLICATION NO. 10/596,614</p>
<p>Christopher Ausschnitt</p>		
<p>FILING 06/19/2006</p>		<p>GROUP ART N/A</p>

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,619,144	09/16/2003	Dvir			
	6,603,529	08/05/2003	Finarov			
	US RE38,153	06/24/2003	Finarov			
	6,556,947	04/29/2003	Scheiner, et al.			
	6,476,920	11/05/2002	Scheiner, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	20020072003	06/13/2002	Brill, et al.			
	20020090744	07/11/2002	Brill, et al.			
	20020171828	11/21/2002	Cohen, et al.			
	20030058454	03/27/2003	Scheiner			

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<p>EXAMINER /Christopher Young/ (06/18/2009)</p>	<p>DATE CONSIDERED 06/18/2009</p>
---	--

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596.614
APPLICANT(S) Christopher Ausschnitt		
FILING DATE 06/19/2006		GROUP ART UNIT N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,045,433	04/04/2000	Dvir, et al.			
	6,038,029	03/14/2000	Finarov			
	5,957,749	09/28/1999	Finarov			
	5,867,590	02/02/1999	Eylon			
	6,426,502	07/30/2002	Finarov			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
---	--------------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
	Christopher Ausschnitt	
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,424,417	07/23/2002	Cohen, et al.			
	6,407,809	06/18/2002	Finarov, et al.			
	6,368,181	04/09/2002	Dvir, et al.			
	6,292,265	09/18/2001	Finarov, et al.			
	6,281,974	08/28/2001	Scheiner, et al			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	1) "Phi-Scatterometry for Integrated Linewidth Control in DRAM Manufacturing" Benesch, et al., 2001 IEEE 0-7803-6731 - June 2001 - pp 129 - 132
	2) "Scatterometry Applied To Microelectronics Processing" John R. McNeil, 2000 IEEE, 0-7803-6252 - July 2000 pp. 37-38
	3) "Accuracy and Precision of Scatterometer Measurements Relative to Conventional CD Metrology" Hayes, et al., 2000 IEEE, 0-7803-6252- July 2000, pp. 39 - 40
	4) "Distinguishing Dose From Defocus for In-Line Lithography Control" C.P. Ausschnitt, Part of the SPIE Conference on Metrology, Inspection & Process Control for Microlithography XIII, Santa Clara, CA, March 1999, SPIE Vol. 3677

EXAMINER

/Christopher Young/ (06/18/2009)

DATE CONSIDERED

06/18/2009

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	ATTY DOCKET NO. FIS920020101US1	APPLICATION NO. 10/596,614
	Christopher Ausschnitt	
	FILING 06/19/2006	GROUP ART N/A

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,166,801	12/26/2000	Dishon, et al.			
	6,100,985	08/08/2000	Scheiner, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	20010026364	10/04/2001	Ravid, et al.			
	20020005957	01/17/2002	Finarov, et al.			
	20020033450	03/21/2002	Finarov, et al.			
	20010015811	08/23/2001	Ravid, et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	5) "Yield Prediction Using Critical Area Analysis With Inline Defect Data" Zhou, et al., 2002 IEEE/SEMI Advanced Semiconductor Manufacturing Conference, pp. 82 - 86
	6) "Specular Spectroscopic Scatterometry" Niu, et al., IEEE Transactions on Semiconductor Manufacturing, Vol. 14, No. 2, May 2001, pp. 97 - 111
	7) "Shallow Trench Isolation Scatterometry Metrology in a High Volume Fab" Lensing, et al., 2001 IEEE, 07803-6731- June 2001, pp 195 - 198
	8) "Full Profile Inter-layer Dielectric CMP Analysis" Chang, et al., 2001 IEEE, 0-7803-6731 - June 2001, pp. 133 - 136

EXAMINER

/Christopher Young/ (06/18/2009)

DATE CONSIDERED

06/18/2009

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

10596614 - GAU: 1795 INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. FIS920020101US1		APPLICATION NO. 10/596,614	
				Christopher Ausschnitt			
				FILING 06/19/2006		GROUP ART N/A	

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			
			9) "A New Approach To Pattern Metrology" C. Ausschnitt - Proc. SPIE 5375-7 - February 23, 2004, Santa Clara, CA - pp. 1 - 15

EXAMINER /Christopher Young/ (06/18/2009)	DATE CONSIDERED 06/18/2009
---	--------------------------------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.